

Quarterly Reliability Monitoring Results

Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory Assembly reliability labs Based on AEC-Q101 Test		User Part Number						
		MMBZ16VTAL-Q						
		Part Description						
		Nexperia DHAM	Protection					
		SMD package						
		Test Conditions	Duration	# Lots	# Quantity	# Rejects		
	TEST							
	Pre- and Post-Stress							
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		JESD22-A113						
		Bake Tamb = 125 °C	24 hours					
" * 4	PC Preconditioning	Soak Tamb = 85 °C, RH = 85% Reflow soldering	168 hours 3 cycles	120	24620			
# A1	Preconditioning		3 cycles	438	24630	0		
İ	HTRB	MIL-STD-750-1 M1038 Method A						
		Tj = Tjmax, Vr = 100% of max. datasheet						
# B1	Bias	reverse voltage	1000 hours	166	10040	0		
,, DI			1000 110013	100	10010	•		
	тс	JESD22-A104						
# A4	Temperature Cycling	-65 °C to Tjmax, not to exceed 150°C	1000 cycles	131	7760	0		
	UHAST	JESD22-A118						
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %	— 96 hours	131	7760	0		
		JESD22-A102						
	AC	Tamb = 121 °C, RH = 100 %						
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)						
	H3TRB	JESD22-A101						
" AO II	High Humidity High Temperature Reverse Bias	Tamb = 85 °C, RH = 85%, VR = 80 % of rated reverse voltage ^[1]	1000	101	7760			
# A2 alt	Temperature Reverse Bias		1000 hours	131	7760	0		
	IOL	MIL-STD-750 Method 1037 ton = toff, devices powered to insure ΔT_j =						
# A5	Intermittent Operating Life		1000 hours	n.a.	n.a.	n.a.		
# A3	2commetene operating Life	200 0.0. 10000 07000	1000 Hours	11.d.	ıı.d.	11.4.		
	RSH	JESD22-A111						
# C8	Resistance to Solder Heat		10 s	45	1350	0		
50	SD		-20	.5		-		
# C10	Solderability	J-STD-002		111	1110	0		

^[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Protection	10040	0	0,42	2,36E+09

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